



ANSI/EIA-364-99-1999(R2006)

Approved: April 23, 1999

Reaffirmed: March 31, 2006

EIA STANDARD

TP-99

Gage Location and Retention Test Procedure for Electrical Connectors

EIA-364-99

JUNE 1999

ELECTRONIC INDUSTRIES ALLIANCE

**Electronic Components, Assemblies, Equipment & Supplies
Association**



Electronic Components, Assemblies, Equipment & Supplies Association
A Sector of the Electronic Industries Alliance

EIA-364-99

NOTICE

EIA Engineering Standards and Publications are designed to serve the public interest through eliminating misunderstandings between manufacturers and purchasers, facilitating interchangeability and improvement of products, and assisting the purchaser in selecting and obtaining with minimum delay the proper product for his particular need. Existence of such Standards and Publications shall not in any respect preclude any member or nonmember of EIA from manufacturing or selling products not conforming to such Standards and Publications, nor shall the existence of such Standards and Publications preclude their voluntary use by those other than EIA members, whether the standard is to be used either domestically or internationally.

Standards and Publications are adopted by EIA in accordance with the American National Standards Institute (ANSI) patent policy. By such action, EIA does not assume any liability to any patent owner, nor does it assume any obligation whatever to parties adopting the Standard or Publication.

This EIA Standard is considered to have International Standardization implication, but the International Electrotechnical Commission activity has not progressed to the point where a valid comparison between the EIA Standard and the IEC document can be made.

This Standard does not purport to address all safety problems associated with its use or all applicable regulatory requirements. It is the responsibility of the user of this Standard to establish appropriate safety and health practices and to determine the applicability of regulatory limitations before its use.

(From Standards Proposal No. 4143, formulated under the cognizance of the CE-2.0 National Connector Standards Committee.)

Published by

©ELECTRONIC INDUSTRIES ALLIANCE 1999
Engineering Department
2500 Wilson Boulevard
Arlington, VA 22201

**PRICE: Please refer to the current
Catalog of EIA Electronic Industries Alliance Standards and Engineering Publications
or call Global Engineering Documents, USA and Canada (1-800-854-7179)
International (303-397-7956)**

All rights reserved
Printed in U.S.A.

PLEASE!

DON'T VIOLATE
THE
LAW!

This document is copyrighted by the EIA and may not be reproduced without permission.

Organizations may obtain permission to reproduce a limited number of copies through entering into a license agreement. For information, contact:

Global Engineering Documents
15 Inverness Way East
Englewood, CO 80112-5704 or call
U.S.A. and Canada 1-800-854-7179, International (303) 397-7956

CONTENTS

Clause		Page
1	Introduction	1
1.1	Scope	1
1.2	Object	1
2	Test resources	1
2.1	Equipment	1
3	Test specimen	1
3.1	Description	1
3.2	Preparation	2
3.3	Mounting	2
4	Test procedure	2
4.1	Gage location test	2
4.2	Gage retention test	2
5	Details to be specified	2
6	Test documentation	3

(This page left blank)

TEST PROCEDURE No. 99

GAGE LOCATION AND RETENTION TEST PROCEDURE
FOR
ELECTRICAL CONNECTORS

(From EIA Standards Proposal No. 4143, formulated under the cognizance EIA CE-2.0 Committee on National Connector Standards.)

1 Introduction

1.1 Scope

This standard establishes a method of determining the gage location and retention of electrical connectors.

1.2 Object

The object of this test procedure is to determine the ability of a connector to comply with specified location and retention measurements through the use of location and retention test gages.

2 Test resources

2.1 Equipment

2.1.1 Retention test gage.

2.1.2 Location test gage.

2.1.3 Measurement device, English or metric, as applicable.

2.1.4 Force gage with accuracy of ± 2 percent.

2.1.5 Test fixture.

3 Test specimen

3.1 Description

A test specimen shall consist of a plug or receptacle.

3.2 Preparation

The cavities to be tested shall be unwired, without accessory hardware, and unmated. All applicable contacts shall be installed.

3.3 Mounting

The unmated test specimen shall be mounted in a position of axial alignment with gage. Sufficient clearance shall be provided under the test specimen to allow for any push through that may occur.

4 Test procedure

4.1 Gage location test

Applicable test gages specified in the referencing document shall be installed in three randomly selected cavities of each contact size of each connector. With the gages fully seated against the contact retention device, the axial location of the front of the gages shall be measured relative to the specified reference point indicated in the reference document.

4.2 Gage retention test

Applicable test gages specified shall be installed in three randomly selected cavities in each connector. The axial load specified shall be applied to the individual test gages in both directions. The load shall be applied at a rate of approximately 0.45 kilogram per second (1 pound per second) until the specified load has been reached. Gage displacement shall be measured with respect to the connector shell after an initial load of 0.91 kilogram (2 pounds) has been applied to assure that all slack has been taken up. The axial displacement of the gage shall not exceed 0.30 millimeter (0.012 inch) or as specified in the referencing document. No damage to gage or insert shall occur.

5 Details to be specified

The following details shall be specified in the referencing document:

5.1 Test gages; see 4.1 and 4.2

5.2 Reference point for gage location measurement; see 4.1

5.3 Maximum allowable displacement after initial load has been applied, if other than specified herein; see 4.2

5.4 Applied axial load; see 4.2

6 Test documentation

Documentation shall contain the details specified in clause 5, with any exceptions, and the following:

6.1 Title of test

6.2 Specimen description; include fixture, if applicable

6.3 Test equipment used, and date of last and next calibration

6.4 Values and observations

6.4.1 Measured gage displacement

6.5 Name of operator and date of test

EIA Document Improvement Proposal

If in the review or use of this document, a potential change is made evident for safety, health or technical reasons, please fill in the appropriate information below and mail or FAX to:

Electronic Industries Alliance
Engineering Department – Publications Office
2500 Wilson Blvd.
Arlington, VA 22201
FAX: (703) 907-7501

Document No.	Document Title:
Submitter's Name:	Telephone No.: FAX No.: e-mail:
Address:	
Urgency of Change: Immediate: <input type="checkbox"/> At next revision: <input type="checkbox"/>	
Problem Area: a. Clause Number and/or Drawing: b. Recommended Changes: c. Reason/Rationale for Recommendation:	
Additional Remarks:	
Signature:	Date:
<div style="text-align: center;">FOR EIA USE ONLY</div> Responsible Committee: Chairman: Date comments forwarded to Committee Chairman:	

